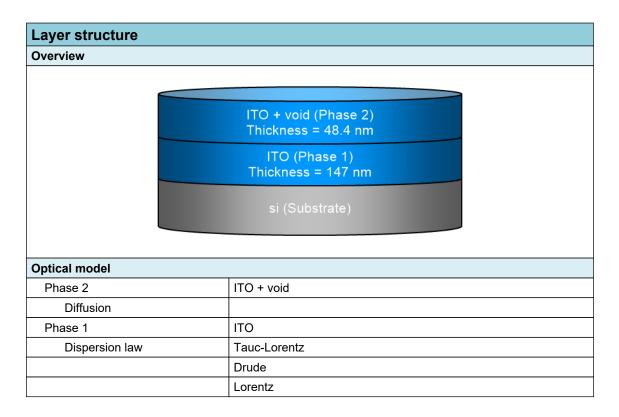


SEA regression report summary

Sample ID 001f-int-i 70° 1

Details				
Software and regression log				
Software about	Semilab - Spectroscopic Ellipsometry Analyzer - SEA			
Software version	1.7.1			
Officially licensed to	MIT			
Operator	operator			
Date and time of regression	14-07-2021 14:09			
Comments				





Regression results

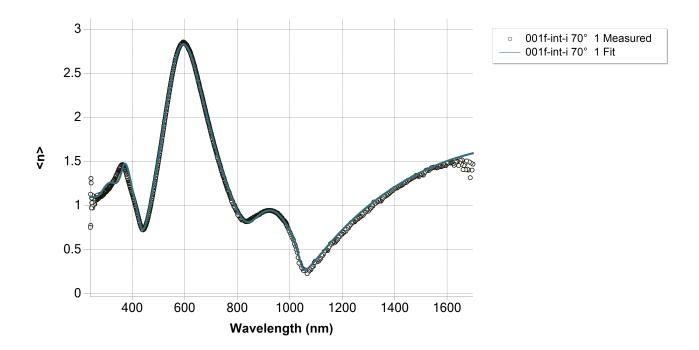
Measurement information					
Measurement file path	C:\Users\emmabat\itc	-si\001f	-int-i.smdx		
Angle of Incidence	70°				
Regression details					
Regression 1 (EllipsoReflectance)					
Wavelength range	239.84 - 1698.83 nm				
Angle of Incidence	70°				
Fit to	<n>, <k></k></n>				
Angular Aperture	0°				
Fit algorithm	LMA				
Results					
Parameters	Value	Fitted	2 σ confidence limit	Unit	
Model					
AOI Shift	0			0	
Angular Aperture	0			0	
Phase 2 (ITO + void)		-			
Thickness	48.433	Х	0.29338	nm	
Depolarization coefficient	0.33333				
Concentration 1	0.5				
Concentration 2	0.5				
Phase 1 (ITO)				L	
Thickness	146.951	Х	0.79789	nm	
A (eV)	499.9547			eV	
E0 (eV)	6.0053			eV	
C (eV)	61.46965	Х	4.34175	eV	
Eg (eV)	3.52296	Х	0.19442	eV	
E_p (eV)	1.04931	Х	0.0077228	eV	
Ε_Γ (eV)	0.4947	Х	0.013188	eV	
	1.04486	Х	0.033353		
E0 (eV)	4.08149	Х	0.025332	eV	
Γ (eV)	1.23919	Х	0.027721	eV	
Eps_inf	0				
Derived parameters	Value				
Phase 2 (ITO + void)					
n @ 632.8 nm	1.4137				
k @ 632.8 nm	0.0389				
Phase 1 (ITO)	<u> </u>				
n @ 632.8 nm	1.8695				
k @ 632.8 nm	0.0846				
Substrate (si)	0.0010				
n @ 632.8 nm	3.8811				
k @ 632.8 nm	0.0195				
Drude derived parameters	Value			Unit	
Phase 1 (ITO)					
Conductivity (S/m)	2.994E+04 ± 1238.8915			S/m	

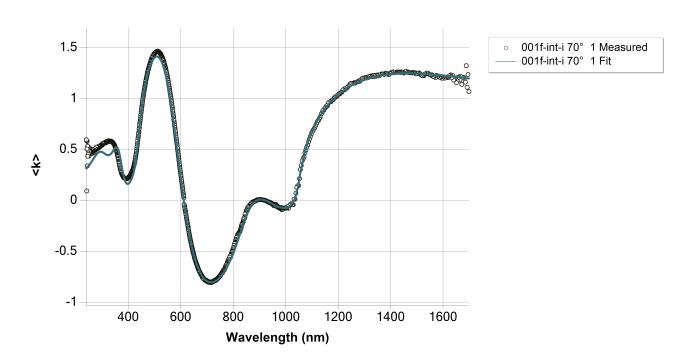


Resistivity (mΩ.cm)	3.34 ± 0.1382	mΩ.cm		
Resistance (Ω/sq)	227.2888 ± 10.6391	Ω/sq		
N type dopant concentration (at/cm3)	1.9963E+20 ± 2.9386E+18	at/cm3		
P type dopant concentration (at/cm3)	2.9546E+20 ± 4.3491E+18	at/cm3		
N type dopant mobility (cm2/Vs)	9.3607 ± 0.4111	cm2/Vs		
P type dopant mobility (cm2/Vs)	6.3248 ± 0.2778	cm2/Vs		
Fit quality				
R^2	0.99581			
RMSE	0.04317			



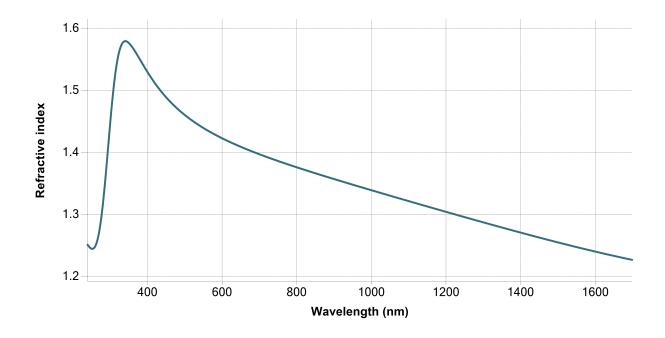
Regression graphs

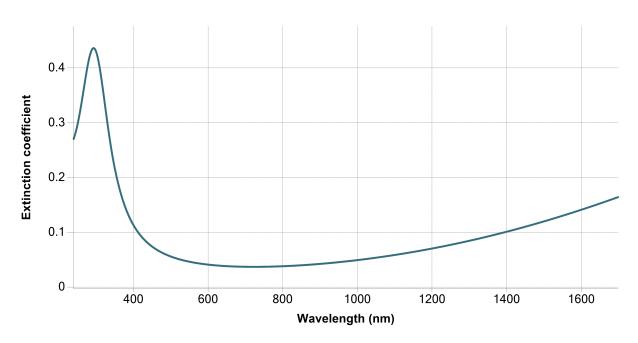






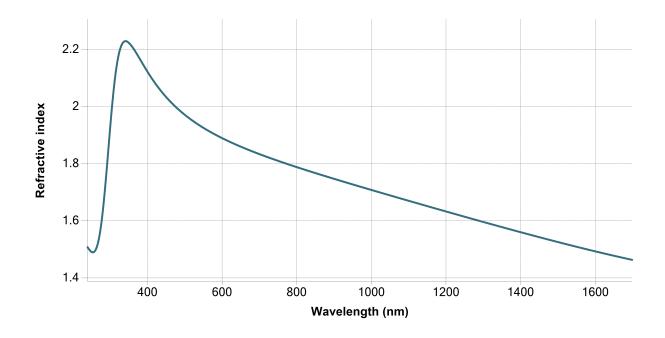
Phase 2 (ITO + void) - Dispersion graphs

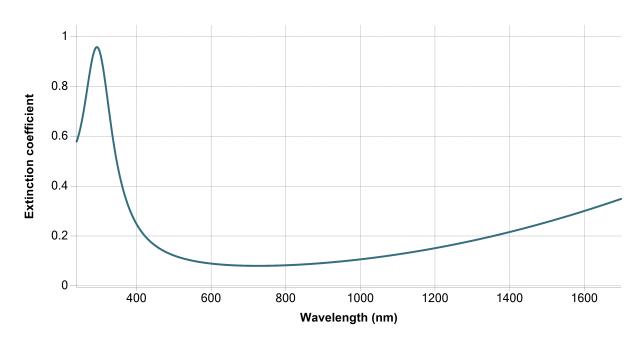






Phase 1 (ITO) - Dispersion graphs







Substrate (si) - Dispersion graphs







Correlation coefficients	
Ph2 - ITO + void - Thickness Ph1 - ITO - Thickness	-0.507
Ph2 - ITO + void - Thickness Ph1 - Tauc-Lorentz[1] - C (eV)	0.0157
Ph2 - ITO + void - Thickness Ph1 - Tauc-Lorentz[1] - Eg (eV)	-0.0056
Ph2 - ITO + void - Thickness Ph1 - Drude[2] - E_p (eV)	-0.386
Ph2 - ITO + void - Thickness Ph1 - Drude[2] - E_Γ (eV)	-0.097
Ph2 - ITO + void - Thickness Ph1 - Lorentz[3] - f	0.1035
Ph2 - ITO + void - Thickness Ph1 - Lorentz[3] - E0 (eV)	-0.1344
Ph1 - ITO - Thickness Ph1 - Tauc-Lorentz[1] - C (eV)	-0.2408
Ph1 - ITO - Thickness Ph1 - Tauc-Lorentz[1] - Eg (eV)	0.2732
Ph1 - ITO - Thickness Ph1 - Drude[2] - E_p (eV)	0.5616
Ph1 - ITO - Thickness Ph1 - Drude[2] - E_Γ (eV)	0.5503
Ph1 - ITO - Thickness Ph1 - Lorentz[3] - f	-0.0064
Ph1 - ITO - Thickness Ph1 - Lorentz[3] - E0 (eV)	0.403
Ph1 - Tauc-Lorentz[1] - C (eV) Ph1 - Tauc-Lorentz[1] - Eg (eV)	-0.9873
Ph1 - Tauc-Lorentz[1] - C (eV) Ph1 - Drude[2] - E_p (eV)	-0.4765
Ph1 - Tauc-Lorentz[1] - C (eV) Ph1 - Drude[2] - E_Γ (eV)	0.0642
Ph1 - Tauc-Lorentz[1] - C (eV) Ph1 - Lorentz[3] - f	-0.7505
Ph1 - Tauc-Lorentz[1] - C (eV) Ph1 - Lorentz[3] - E0 (eV)	-0.5943
Ph1 - Tauc-Lorentz[1] - Eg (eV) Ph1 - Drude[2] - E_p (eV)	0.4237
Ph1 - Tauc-Lorentz[1] - Eg (eV) Ph1 - Drude[2] - Ε_Γ (eV)	-0.0441
Ph1 - Tauc-Lorentz[1] - Eg (eV) Ph1 - Lorentz[3] - f	0.8275
Ph1 - Tauc-Lorentz[1] - Eg (eV) Ph1 - Lorentz[3] - E0 (eV)	0.6776
Ph1 - Drude[2] - E_p (eV) Ph1 - Drude[2] - Ε_Γ (eV)	0.2157
Ph1 - Drude[2] - E_p (eV) Ph1 - Lorentz[3] - f	0.0886
Ph1 - Drude[2] - E_p (eV) Ph1 - Lorentz[3] - E0 (eV)	0.3347
Ph1 - Drude[2] - E_Γ (eV) Ph1 - Lorentz[3] - f	-0.2509
Ph1 - Drude[2] - E_Γ (eV) Ph1 - Lorentz[3] - E0 (eV)	-0.0525
Ph1 - Lorentz[3] - f Ph1 - Lorentz[3] - E0 (eV)	0.7841